In re Appln. of TAKEUCHI et al. Application No. Unassigned

ABSTRACT AMENDMENTS

Replace the Abstract with:

In a method of evaluating a piezoelectric field, a non-destructive spectrometry of piezoelectric fields is performed in a semiconductor heterojunction using a technique different from PR spectroscopy. In the method, at first, first and second absorption spectra are measured by irradiating the sample with infrared light to a sample with at first and second angles, respectively. Then, a peak position of an absorption band having incident-angle dependent intensity is specified, based on the first and second absorption spectra. Thus, the piezoelectric field strength is obtained based on an equation of energy-level. The equation represents using a relationship between the piezoelectric field and an electron energy level corresponding to the peak position.